

L Number	Hits	Search Text	DB	Time stamp
1	8	382/150.ccls. and ((measur\$4 or determin\$7) near2 (height\$1) with (solder\$3))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/12 14:33
2	0	382/150.ccls. and ((measur\$4 or determin\$7 or detect\$5) near2 (thick\$6) with (plat\$3))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/12 14:34
3	7223	((measur\$4 or determin\$7 or detect\$5) near2 (thick\$6) with (plat\$3))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/12 14:36
4	0	382/141.ccls. and (382/150.ccls. and ((measur\$4 or determin\$7 or detect\$5) near2 (thick\$6) with (plat\$3)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/12 14:34
5	3	382/141.ccls. and (((measur\$4 or determin\$7 or detect\$5) near2 (thick\$6) with (plat\$3)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/12 14:34
6	3357	((measur\$4 or determin\$7 or detect\$5) near2 (thick\$6) near2 (plat\$3))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/12 14:36
7	81	((measur\$4 or determin\$7 or detect\$5) near2 (thick\$6) near2 (plat\$3)) and (image near process\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/12 14:48
8	1	((measur\$4 or determin\$7 or detect\$5) near2 (thick\$6) near2 (plat\$3)) same (inspect\$5) same (image\$1 imaging)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/12 15:09
9	49	((measur\$4 or determin\$7 or detect\$5) near2 (thick\$6) near2 (plat\$3)) same (inspect\$5)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/12 14:50
28	4	((measur\$4 or determin\$7 or detect\$5) near2 (thick\$6) near2 (plat\$3)) same (inspect\$5) same (image\$1 imaging ccd camera\$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/12 15:24
29	221	((measur\$4 or determin\$7 or detect\$5) near2 (thick\$6)) same (inspect\$5) same (image\$1 imaging ccd camera\$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/12 15:13
30	2	5450205.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/12 15:13
63	9	((measur\$4 or determin\$7 or detect\$5) near2 (thick\$6)) and 382/150.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/12 15:28
64	7	((measur\$4 or determin\$7 or detect\$5) near2 (thick\$6)) and 382/150.ccls.) and height\$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/12 15:28

67	1655	((detect\$3 determin\$6 measur\$6) near2 (thick\$4 width\$1) near2 plate\$1)	USPAT	2004/10/12 16:04
68	4	((detect\$3 determin\$6 measur\$6) near2 (thick\$4 width\$1) near2 plate\$1) with (camera\$1 or ccd\$1))	USPAT	2004/10/12 17:01
73	75	382/146.ccls.	USPAT	2004/10/12 17:11
74	2138	356/237.1.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/12 17:21
75	5152	inspect\$4 near4 ((electrode\$1 near plat\$4) or batter\$4 or (power near plate\$1) or anode\$1 or cathode\$1 or cell\$1 or (secondary near cell\$1) or (fuel near cell\$1))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/12 17:21
76	1277	inspect\$4 near4 ((electrode\$1 near plat\$4) or batter\$4 or (power near plate\$1) or (secondary near cell\$1) or (fuel near cell\$1))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/12 17:21
77	1047	inspect\$4 near3 ((electrode\$1 near plat\$4) or batter\$4 or (power near plate\$1) or (secondary near cell\$1) or (fuel near cell\$1))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/12 17:22
78	42	(inspect\$4 near2 ((electrode\$1 near plat\$4) or batter\$4 or (power near plate\$1) or (secondary near cell\$1) or (fuel near cell\$1))) and (camera)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/12 17:22
79	0	"411073948"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/12 17:22

87	55	382/143.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/10/12 17:24
88	726	inspect\$4 near2 ((electrode\$1 near plat\$4) or batter\$4 or (power near plate\$1) or (secondary near cell\$1) or (fuel near cell\$1))	USPÄT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/10/12 17:24
89	165	356/237.1.ccls. and ((electrode\$1 near plat\$4) or batter\$4 or (power near plate\$1) or anode\$1 or cathode\$1 or cell\$1 or (secondary near cell\$1) or (fuel near cell\$1))	USPÄT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/10/12 17:24
90	10	(inspect\$4 near2 ((electrode\$1 near plat\$4) or batter\$4 or (power near plate\$1) or (secondary near cell\$1) or (fuel near cell\$1))) and (image near process\$3)	USPÄT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/10/12 17:24
91	63	(inspect\$4 near2 ((electrode\$1 near plat\$4) or batter\$4 or (power near plate\$1) or (secondary near cell\$1) or (fuel near cell\$1))) and (image\$1 or imag\$3 or ccd\$1)	USPÄT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/10/12 17:24
92	49	(inspect\$4 near2 ((electrode\$1 near plat\$4) or batter\$4 or (power near plate\$1) or (secondary near cell\$1) or (fuel near cell\$1))) and (camera\$1)	USPÄT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/10/12 17:24
93	2	"11073948"	USPÄT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/10/12 17:24
94	1	1999-250478.NRAN.	DERWENT	2004/10/12 17:24
95	82	382/150.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/10/12 17:24
96	3	382/150.ccls. and (((measur\$4 or determin\$7) near2 (height\$1) with (solder\$3)) same (referenc\$4))	USPÄT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/10/12 17:24